### Charge-imbalance e ects in intrinsic Josephson system s

S. Rother, Y. Koval, P. Muller

Physikalisches Institut III, Universitat Erlangen-Nurnberg, Erlangen D-91058, Germany

R.Kleiner

Physikalisches Institut, Universitat Tubingen, D-72076 Tubingen, Germany

D.A.Ryndyk, J.Keller

Institut fur Theoretische Physik, Universitat Regensburg, D-93040 Regensburg, Germany

C. Helm

Institut fur Theoretische Physik, ETH Zurich, CH-8093 Zurich, Switzerland (D ated: A pril 14, 2024)

We report on two types of experiments with intrinsic Josephson systems made from layered high-T<sub>c</sub> superconductors which show clear evidence of nonequilibirum e ects: 1. In 2-point m easurem ents of IV-curves in the presence of high-frequency radiation a shift of the voltage of Shapiro steps from the canonical value  $V_s = hf=(2e)$  has been observed. 2. In the IV-curves of double-mesa structures an in uence of the current through one mesa on the voltage measured on the other m esa is detected. Both e ects can be explained by charge-in balance on the superconducting layers produced by the quasi-particle current, and can be described successfully by a recently developed theory of nonequilibrium e ects in intrinsic Josephson systems.

PACS num bers: 74.80D m, 74.40.+ k, 74.50.+ r, 74.72 Fq, 74.72 Hs

I. IN TRODUCTION

In the strongly anisotropic cuprate superconductors  $B_{1/2}Sr_2CaCu_2O_{8+}$  (BSCCO) and  $T_{1/2}Ba_2Ca_2Cu_3O_{10+}$ (TBCCO) the CuO<sub>2</sub> layers together with the interm ediate material form a stack of Josephson junctions. In the presence of a bias current perpendicular to the layers each junction of the stack is either in the resistive or in the superconducting state leading to the well-known multibranch structure of the IV-curves.<sup>1,2,3</sup>

In the case of weakly coupled layers we expect that the bias current generates charge accum ulation on the layers between a resistive and superconducting junction. As the current through a resistive junction is carried mostly by quasi-particles, while the current through a barrrier in the superconducting state is carried by Cooper-pairs, we expect two types of non-equilibrium e ects: 1. charge uctuations of the superconducting condensate, which can be expressed by a shift of the chemical potential of the condensate and 2. charge-im balance between electron-and hole-like quasiparticles.

Non-equilibrium e ects in layered superconductors have been discussed in a number of papers in various contexts with dierent methods and approximations.<sup>4,5,6,7,8,9,10,11</sup> In a recent theoretical paper<sup>12</sup> we have investigated in particular the consequences of non-equilibrium e ects on experiments with stationary currents. We found that in this case only the charge-in balance is in portant and leads to a change in the voltage, while the shift of the chem ical potential has no in uence on the measured voltage. The latter determines e.g. the dispersion of longitudinal Josephson plasm a waves<sup>4</sup> and can be observed in som e optical properties.13,14

In this paper we report on new experim ents which show clear evidence of non-equilibrium e ects for stationary currents and which can be explained by charge-im balance on the superconducting layers. In the rst type of experim ents Shapiro steps produced by high-frequency irradiation are measured in mesa structures of BSCCO with gold contacts. Here a shift V of the step-voltage  $V_{s} = hf = (2e)$ V from its canonical value hf = (2e) is observed, which can be traced back to a change of the contact resistance due to charge-in balance on the rst superconducting layer. In another type of experiments current-voltage curves are m easured for two m esas structured close to each other on the same base crystal. Here an in uence of the current through one mesa on the voltage drop on the otherm esa has been m easured which can be explained by charge-im balance on the rst common superconducting layer of the base crystal. Both experim ents allow to m easure the charge-im balance relaxation rate.

W e start with a brief sum m ary of the theory<sup>12</sup> which will be used in the following. Then the sample preparation and the di erent experim ents are described and discussed. From the experiments the charge-imbalance relaxation time will be determ ined.

#### II. OUTLINE OF THE THEORY

Let us consider a stack of superconducting layers n = 1;2:::w it a norm all electrode n = 0 on top. The basic quantity which determ ines the Josephson e ect of a junction between layern and n + 1 is the gauge invariant phase di erence

$$n_{n+1}(t) = n(t)$$
  $n+1(t) = \frac{2e}{h} \int_{-n}^{2} dz A_z(z;t);$  (1)

where  $_{n}$  (t) is the phase of the order parameter on layern and  $A_{z}$  (z;t) is the vector potential in the barrier. For the time derivative of  $_{n;n+1}$  one obtains the general Josephson relation:

$$_{n,n+1} = \frac{2e}{h} V_{n,n+1} + _{n+1} n :$$
 (2)

Here

$$V_{n;n+1} = dzE_{z}(z;t);$$
 (3)

$$_{n}(t) = _{n}(t) \frac{h}{2e} - (t);$$
 (4)

are the voltage and the gauge invariant scalar potential,  $_n$  (t) is the electrical scalar potential. The quantity e  $_n$  can be considered as shift of the chem ical potential of the superconducting condensate (in this paper the charge of the electron is written as e).

The total charge uctuation  $_n$  on layer n consists of charge uctuations of the condensate and of charge uctuations of quasi-particles. It is convenient to express the latter also by a kind of potential  $_n$  writing

$$n = 2e^{2}N(0)(n n)$$
: (5)

W ith help of the M axwell equation (d is the distance between the layers, the dielectric constant of the junction)

$$_{n} = \frac{0}{d} (V_{n;n+1} \quad V_{n-1;n})$$
 (6)

the generalized Josephson relation now reads:

$$\frac{h}{2e^{-n;n+1}} = (1+2)V_{n;n+1} \qquad (V_{n-1;n} + V_{n+1;n+2}) + \frac{h}{n+1} \qquad (7)$$

with  $= {}_{0}=(2e^{2}N\ (0)d)$ . It shows that the Josephson oscillation frequency is determined not only by the voltage in the same junction but also by the voltages in neighboring junctions. Furthermore it is in uenced by the quasi-particle potential on the layers. If we neglect the latter we obtain for  $_{-n,n+1}$  the same result as in Ref. 4.

These equations for the voltage between the layers have to be supplemented by an equation for the current density: in the stationary state (no displacement current) it can be written  $as^{12}$ 

$$j_{n;n+1} = j_{c} \sin_{n;n+1} + \frac{n;n+1}{d} (1+2) V_{n;n+1} \qquad (V_{n-1;n} + V_{n+1;n+2}) : (8)$$

Here the quasi-particle current between layers n and n+1 is driven not only by the voltage  $V_{n,n+1}$  between the layers but also by additonal terms which result from the charge uctuation on the two layers. In the stationary state the dc-density  $j_{n,n+1}$  is the same for all barriers and is equal to the bias current density j. If the Josephson junction is in the resistive state we may neglect the dc-component of the supercurrent density in (8) for junctions with a large M cCumber parameter  $_{c}$  1. Then we obtain:

$$\frac{jd}{n;n+1} = (1+2)V_{n;n+1} \qquad (V_{n-1;n} + V_{n+1;n+2}): (9)$$

For the junction between the norm all electrode (n = 0) and the rst superconducting layer (n = 1) we may neglect charge uctuations on the form er and obtain for the current:

$$\frac{jd}{0;1} = (1 + )V_{0;1} V_{1;2}:$$
(10)

F inally we need an equation of m otion for the quasiparticle charge. Here we consider a relaxation process between quasi-particle charge and condensate charge within the layer.<sup>15,16,17</sup> In the stationary case the quasi-particle charge is proportional to the charge-im balance relaxation tim e<sub>q</sub> and the di erence between supercurrents ow ing in and out the layer, or equivalently, by the di erence in quasi-particle currents:<sup>12</sup>

$$\begin{array}{rcl} & n & = & (j_{c} \sin_{n \, n \, n + 1} & j_{c} \sin_{n \, 1 \, n}) & q = (2e^{2}N & (0)) \\ & & = & (j_{n \, 1 \, n}^{qp} & q_{n \, n + 1}^{qp}) & q = (2e^{2}N & (0)) \end{array}$$
(11)

In the limit of small non-equilibrium e ects and for T  $T_c$  we may use the approximation  $j_{n,n+1}^{qp}$  '  $n_{n,n+1}V_{n,n+1} = j$  for a resistive junction and  $j^{qp}$  ' 0 for a junction in the superconducting state. For example, if a current j is owing from a junction in the resistive state into a junction in the superconducting state, the charge-imbalance potential generated on the superconducting layer between the two junctions is  $n = j_q = (2e^{2}N \ (0))$ .

#### III. SAM PLE PREPARATION AND EXPERIMENTAL SET-UP

Form easuring the intrinsic Josephson e ect in BSCCO we used a mesa geometry. Our base materials were BSCCO single crystals which were grown by standard melting techniques. A fter glueing these crystals on saphire substrates, a 100 nm thin gold layer was thermally evaporated. The mesa was patterned by electron beam lithography and etching by a neutral Ar atom ic beam. As etching rates for gold and BSCCO are known quite exactly, the number of Josephson junctions inside the mesa could be adjusted to be between 5 and 10. To avoid shortcuts between A u leads and the superconducting base crystal an insulating SiD layer was evaporated.

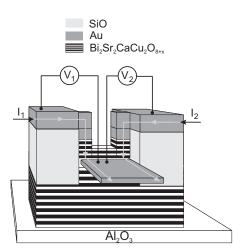


FIG. 1: Sketch of the sample geometry used for injection experiments.

This material was removed from the top of the mesa by lifto . For contact leads a second Au layer was evaporated. The shape of these leads was de ned by standard photolithography and etched by Ar atom s. For samples used in FIR experiments these Au leads were formed in the shape of bow-tie antennas.<sup>18</sup>

A second type of experiments is concerned with induced charge in balance. Here additional preparation steps were necessary. These samples consist of two small m esas on top of one bigger m esa (Fig. 1). To realize this geometry the top layers of a larger mesa (structured as described above) had to be cut in two smaller ones. The whole sample was protected by electron-beam resist except a thin line on top of the big mesa. By etching this sample the larger mesa could be divided in two smaller m esas. To keep a part of the base below the two sm aller ones the etching process had to be controlled precisely. The resistance of the gold lead was recorded during etching show ing the tim e when gold was rem oved and separation of the big m esa began. W ith this technique we were able to structure samples with 5 10  $m^2$  and 4 10  $m^2$ m esas each including about 10 intrinsic Josephson junctions on top of one larger one (10  $10 \text{ m}^2$ , 6 junctions). The gap between the two top mesas was 1 m. All sam ples discussed in this article are listed in Tab. I. The kind of experim ents they are used for are marked by DM (double mesa) and FIR (FIR absorption).

IV -characteristics of our sam ples were recorded by applying dc currents and recording voltages across mesas by digital voltmeters. If not mentioned otherwise all measurements were performed at a temperature of 4.2 K.

As radiation source for experiments presented in Section 4.1 we used a far-infrared laser which was optically pumped by a  $CO_2$  laser. To minimize power losses we used a polyethylene lens producing a parallel beam. Inside the optical cryostat the samples were xed in the center of a silicon hyperhem ispherical lens to focus the radiation onto the mesa.<sup>18</sup> For some samples we used a

Sam ples area (m<sup>2</sup>) # jj experim ents

-			55	-
SR 102_3	10	10 (B)	6	DM
SH 104	4	10 (M 1)	10	DM
	5	10 (M 2)	10	DM
	7	6 <b>(</b> B)	11	DM
	2	6 <b>(</b> M 1)	3	DM
	3	4 <b>(</b> M 2)	4	DM
# 32	8	8	8	FIR
# 39	10	10	20	FIR
# 20	10	10	11	FIR

TABLE I: Table of sam ples described in this article. The area of the m esas and the num ber of junctions (# j) containing it are listed together with the kind of experiments they were used for.

very sensitive setup to detect Shapiro steps and to determ ine voltage of these resonances very precisely. For this purpose the laser beam was modulated by an optical chopper with a xed frequency. With the chopper frequency as external reference, the voltage across the junction was connected to the input of a lock-in am pli er (LI). As the LI analyzes voltage changes occurring with the chopper frequency the output signal  $V_{\rm LI}$  exhibits a point-symmetric structure. Thus the LI output signal represents the voltage di erence between IV - characteristics with and without laser radiation. The voltage of the Shapiro step can easily be identi ed as the symmetry point of this signal.

# IV. EXPERIMENTAL RESULTS

### A. Shapiro steps

O ur experim ents with high frequency electrom agnetic radiation have been carried out with three sam ples # 32 (8 8 m<sup>2</sup>), # 39 (10 10 m<sup>2</sup>) and # 20 (10 10 m<sup>2</sup>). We rst discuss results for sam ple # 32 which consists of eight intrinsic Josephson junctions as can be seen in the IV -characteristics shown in Fig. 2.

The increasing values of critical currents may be explained by the inhom ogeneous etching process during fabrication producing layers with increasing areas from top to bottom of the mesa. Then it is natural to assume that the values of critical currents increase with the position of the junctions inside the mesa. In particular, the rst resistive branch of the IV -characteristics should be assigned to the uppermost Josephson junction of the mesa. The critical current on branch num – ber 0 is strongly suppressed and its IV -curve is linear, while the other branches show the typical non-linear IV – dependence characteristic for a tunneling junction between two superconducting layers with d-wave order param eter. The special behaviour of branch 0 m ight be explained by the assumption that the rst superconduct-

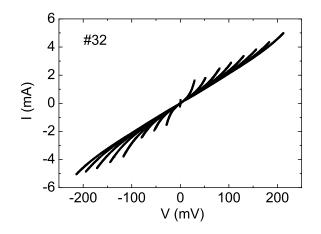


FIG.2: IV characteristic of sample # 32.

ing layer is in proximity contact with the normal gold electrode.

This sample was irradiated with four external frequencies between 584 GHz and 762 GHz. On the IV characteristic we could detect ist order Shapiro steps on the rst resistive branch at an absolute voltage V<sub>S</sub> and current I<sub>S</sub>. To compare the step-voltage with hf=(2e) as predicted by the second Josephson relation the contact voltage V<sub>0</sub> (I) between Au leads and mesa in the superconducting state without radiation had to be measured. The value V<sub>S</sub> = V<sub>S</sub> (I<sub>S</sub>) V<sub>0</sub> (I<sub>S</sub>) can then be compared with hf=(2e). As shown in Fig.3, V<sub>S</sub> evaluated for this sample is strictly lower than hf=(2e) for all four frequencies. The relative shift is approximately 3%.

This downshift can be explained if we assume that the Josephson junction in the resistive state which is locked to the external radiation with frequency f is close to the norm al electrode, i.e. between the rst and second superconducting layer. For this junction we have

$$\frac{\text{hf}}{2\text{e}} = (1+2)V_{1;2} \qquad (V_{0;1}+V_{2;3}) + 2 \qquad 1; \quad (12)$$

while for the other junctions, which are in the superconducting state, we use

$$0 = (1 + 2) V_{n;n+1} \qquad (V_{n-1;n} + V_{n+1;n+2}) + {}_{n+1} \qquad (13)$$

for n 2. Adding up these equations together with the current relation for the contact with the norm alelectrode (10) we obtain for the total voltage:

$$V_{\rm S} = \frac{\rm jd}{\rm_{0;1}} + \frac{\rm hf}{\rm 2e}$$
: (14)

Here we have assumed that  $_{n} = 0$  form 3. The contribution of  $_{2}$  drops out. Finally, the charge-im balance potential  $_{1}$  vanishes on the rst layer since the on-and o - ow ing quasiparticle currents are equal,  $j_{0,1}^{qp} = j_{1,2}^{qp} = j$ .

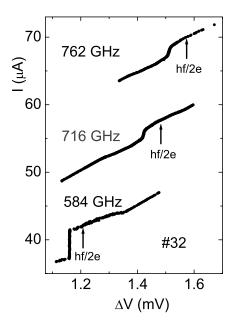


FIG. 3: Voltages of Shapiro steps measured on IV characteristic of sample # 32 compared to hf=(2e) (for the higher frequencies the current axis is shifted).

We have to compare this result with the voltage measured in the absence of high-frequency irradiation, when all junctions are in the superconducting state. Then (13) holds for n 1. Adding up now equations (13) and (10) we obtain for the total voltage (contact voltage in the superconducting state):

$$V_0 = \frac{jd}{0;1} + 1:$$
(15)

The quasi-particle potential on the rst superconducting layer is now given by  $_1 = j_q = (2e^2N \ (0))$  while  $_n = 0$  for n 2. Subtracting the measured contact voltage from the voltage of the Shapiro step we obtain for the step-voltage:

$$V_{S} = \frac{h!}{2e} \qquad V \qquad (16)$$

with  $V = j_q = (2e^2N(0))$ . The shift is proportional to the life-time of charge-in balance.

Sam ple # 39 consists of 20 intrinsic Josephson junctions. For this sam ple the distribution of critical currents ism ore hom ogeneous (Fig. 4) than for # 32 m aking it in – possible to determ ine the position of the junction generating the rst resistive branch inside the m esa. By using the sensitive m easurement technique with a pulsed laser beam we were able to detect Shapiro steps on the rst resistive branch at three FIR frequencies between 1.40 THz and 1.63 THz. The voltage di erences V<sub>S</sub> of these resonances were calculated as described above. In contrast to # 32 for this sam ple no deviations from hf=(2e)

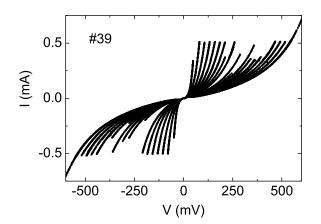


FIG.4: IV characteristic of sample # 39.

were measured. In view of the theory presented above this means, that the resistive junction which is locked to external radiation is not close to the norm all electrode or the charge-im balance time is rather short for this sample.

Finally we want to focus on sam ple # 20 consisting of 11 intrinsic Josephson junctions. The IV-curves of this sam ple show a very hom ogeneous distribution of critical currents making it in possible to assign any branch to a junction at a certain position inside the m esa. How ever, for di erent current cycles (increase  $I_1$  to its maximum value than decrease it zero) two di erent rst branches marked 1a and 1b in Fig. 5 are m easured. This m eans that two di erent junctions in the stack become resistive rst.

We were able to detect Shapiro steps at ve frequencies between 1.27 THz and 1.82 THz on both branches 1a and 1b. Analyzing the voltage dierences V  $_{\rm S}$  we got di erent values for 1a and 1b (Fig. 6). On branch 1a the voltages of Shapiro steps were detected at regular values of hf = (2e) whereas voltages of 1b were shifted to values 3% below hf=(2e). This behaviour can be explained by assuming that in case 1b the junction close to the norm al electrode becom es resistive while in case 1a a junction inside the stack becom es resistive. This assum ption is also in agreem ent with the observation that the voltage of the second branch at the critical current is approxim ately given by the sum of the voltages of 1 a and 1b and the voltage di erences for the higher branches are rather hom ogenous and are close to the value for branch 1a.

We want to mention that we could also measure Shapiro steps on higher resistive branches. Due to slightly varying parameters of dierent resistive Josephson junctions analysis of V  $_{s;n}$  is much more complicated and was not accurate enough to deduce deviations from the second Josephson relation.

F inally we want to point out that a shift in the Shapiro step voltage is only possible, if the resistive junction is close to the norm al electrode. In recent measurements

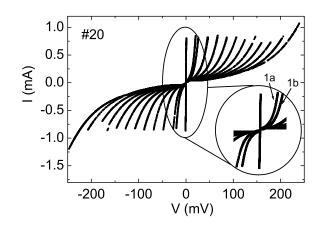


FIG.5: IV characteristic of # 20. Several current cycles are shown in one gure.

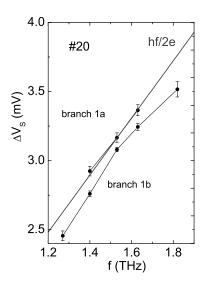


FIG.6: Voltages of Shapiro steps m easured on IV characteristic of sam ple # 20 com pared to hf=(2e). The values strongly depend on which branch 1a or 1b the resonances occured.

of Shapiro steps in step-edge junctions<sup>19</sup> this is di erent. Here the resistive Josephson junction is inside a stack of superconducting layers and hence no shift is observed. Also no shift of Shapiro steps appears in true 4-point m easurem ents and for steps crossing the zero-current line at the point of zero current.<sup>20</sup>

## B. In jection experim ents in double-m esa structures

The geometry of samples used for injection experiments in double-mesa structures is schematically shown in Fig. 1. As results obtained for the diment samples are rather similar, we will discuss only results for sam -

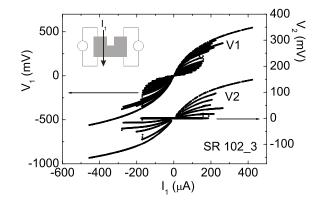


FIG.7: Voltages of M 1 and M 2 during variation of  $I_1$  while  $I_2$  = 0.

ple # SR 102\_3. Here two sm all m esas M 1 of lateral size 5 10 m<sup>2</sup> and M 2 of size 4 10 m<sup>2</sup> were structured on a base m esa B of size 10m 10 m<sup>2</sup>. The currents  $I_{1;2}$  through the m esas M 1 and M 2 and the base m esa B and the corresponding voltages  $V_{1;2}$  can be m easured separately. The brush-like structure of the IV-curves which is sim ilar for the two m esas show s two sets of branches w ith di erent critical currents. These belong to 10 Josephson junctions in M 1 and M 2 and 6 junctions in the base m esa.

To explain the operation of the device we want to start with the case of no current owing through M 2 ( $I_2 = 0$ ). M easuring V<sub>1</sub> and V<sub>2</sub> during variation of  $I_1$  we obtained the curves shown in Fig. 7. V<sub>1</sub> ( $I_1$ ) shows the full set of IV-curves of M 1 and B, while in V<sub>2</sub> ( $I_1$ ) only the resistive junctions of the base mesa B appear. Here V<sub>2</sub> ( $I_1$ ) is in fact a 4-point m easurem ent of the IV-characteristic of the base mesa. Note that as long as the junctions in B are completely superconducting, the voltage V<sub>2</sub> is exactly zero and independent of  $I_1$ . If a sm all current  $I_2$  is applied to M 2, then V<sub>2</sub> ( $I_2$ ) shows the contact resistance between the gold electrode and the mesa. Again the voltage V<sub>2</sub> does not depend on  $I_1$ .

Now a larger bias current is applied to M 2, such that some junctions of M 2 are in the resistive state. Keeping  $I_2$  xed we varied the current  $I_1$ . During the cycling of  $I_1$  junctions in M 1 are switched on and o into the resistive state. From time to time also junctions in the otherm esa M 2 are switched on and o leading to discrete jumps in the voltage  $V_2$ , but otherw ise  $V_2$  is still constant (horizontal line in Fig. 8).

In some cases, however, the voltage on M 2 jumps to an additional branch  $V_2(I_1)$ , which splits o from the constant voltage branch and depends weakly on  $I_1$ . The jump into this branch, which is marked V in Fig. 8, is always triggered by a switch into one of the higher order branches of M 1. Let us note that this happens only if  $I_1$  and  $I_2$  are in opposite direction. In later cycles the branch  $V_2(I_1)$  can also traced out by increasing the current  $I_1$  from zero. In general, several sets of voltage

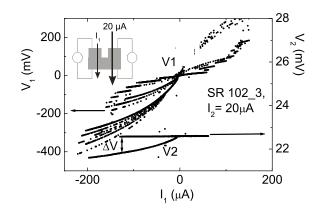


FIG.8: Voltages of M 1 and M 2 during variation of  $I_1$  while two junctions of M 2 are in the resistive state.

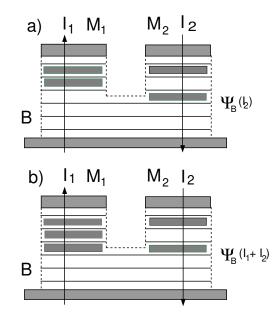


FIG.9: Charge-in balance generated on the rst layer of the base m esa by the currents through m esas M 1 and M 2.

curves with split branches V  $_2$  (I<sub>1</sub>) occur. The voltages of the horizontal branches correspond to di erent numbers of junctions of M 2 beeing in the resistive state at the xed current I<sub>2</sub>. In Fig. 8 only the branch corresponding to two resistive junctions is shown.

The maximum voltage di erence V is much smaller than the voltage between di erent resistive branches in M 2 at the bias current  $I_2$ . It is also much smaller than the voltage of resistive junctions in the base mesa. Therefore the appearence of V<sub>2</sub>( $I_1$ ) must have a di erent origin and can be explained as follows: If the junctions between the low est layers in both mesas M 1 and M 2 and the rst common superconducting layer in B are resistive, then a nonequilibrium potential <sub>B</sub> is generated on the rst superconducting layer of the base mesa. This is illus-

trated in Fig.9: In Fig.9a only the current  $I_2$  contributes to the charge-im balance potential, while in Fig.9b both currents contribute. The generated charge-im balance potential can be measured directly as additional voltage on M 2:

$$V_{2}(I_{1}) = B(I_{1} + I_{2}) B(I_{2});$$
 (17)

<sub>B</sub> (I) = 
$$\frac{I}{A} \frac{q}{2e^2N(0)}$$
: (18)

Here A is the area of the base mesa. In deriving (18) we assumed that the charge-im balance relaxation time is large compared to the di usion time of charge-im balance along the layer.

Finally we want to explain the asymmetry of  $V_2$   $(I_1)$  with respect to the polarity of both currents. The total current  $I_B$  through B is either  $I_1 + I_2$  if the polarity is the same, or  $I_1$  ~~  $\downarrow$  if the polarity is opposite. In the rst case the total current through B is higher. This makes it possible that one junction inside B gets resistive before the critical current of the small mesas is exceeded. This destroys the precondition of a completely superconducting mesa B  $\cdot$  W hen the polarity is opposite the current through B is always smaller than  $I_1$  and junctions in M 1 will get resistive before any junction in B  $\cdot$ 

# C . D eterm ination of the charge-im balance relaxation tim e

Both types of experiments can be used to measure the charge-imbalance relaxation time. From the shift of the Shapiro step we obtain

$$_{q} = V \frac{A}{I} 2e^{2}N$$
 (0); (19)

where A is the area of the mesa. From the injection experiment in the double-mesa structure a similar expression is obtained. This equation contains the unknown density of states N (0) of the two-dimensional electron gas at the Ferm i surface. For a rough estimate we may use the density of states N (0) =  $m = (2 \ h^2)$  of free conduction electrons with mass m, then  $2e^2N$  (0) =  $0.67C^2J^{-1}m^{-2}$ . A lternatively, by using  $= _0 = (2e^2N \ (0)d)$  we can express  $2e^2N$  (0) by the parameter , the dielectric constant

of the barrier and the distance d between superconducting layers. In Ref. 14 the values = 0.4, = 20 have been estimated from re ectivity experiments (for another material). Here it is found that the value of  $_0=(d)$  is rather close to the value of  $2e^2N$  (0) calculated for free conduction electrons, which therefore will be used in the following.

W ith the data of sample # 32: A = 64 m<sup>2</sup>, I = 30 A, V = 50 V we nd  $_{q}$  ' 70 ps. An estimate for the The charge-in balance relaxation time  $_{\rm q}$  describes the recombination of quasi-particles into Cooper pairs. It should be distinguished from the characteristic time for the therm alisation of hot quasi-particles, which is much shorter.<sup>21</sup> Note that in the present case  $_{\rm q}$  is much longer than the period of a Josephson oscillation on a Shapiro step. For the charge-in balance relaxation normally inelastic phonon scattering processes are responsible. It should be noted that in the case of d-wave pairing with an anisotropic gap also elastic in purity scattering contributes.<sup>17</sup>

#### V. SUMMARY

In this paper we have discussed new experiments showing evidence of non-equilibrium e ects in intrinsic Josephson contacts in layered superconductors, which are due to charge-imbalance produced by a stationary bias current. In particular, we have investigated the voltage-position of Shapiro steps in the presence of highfrequency irradiation. In some cases we observed a dow nshift of 3% from the canonical value of hf=(2e). This shift, which is not a violation of the basic Josephson relation, can be explained by charge imbalance on the rst superconducting layer if the Josephson contact is next to the norm al electrode.

In another type of experiment we studied the mutual in uence of currents through two mesas on a common base mesa on the measured voltages. The reults can be explained by charge-imbalance on the rst common superconducting layer of the base mesa. This experiments has some similarity with the classical experiment by Clarke,<sup>15</sup> where charge imbalance is produced in a superconductor by a strong quasi-particle current which is then detected as voltage di erence between a norm al contact and a Josephson contact.

Both experiments allow to measure the chargeimbalance relaxation time which is of the order of 100 ps.

#### A cknow ledgem ents:

This work was supported by the Bayerische Forschungsstiftung (SR), the Germ an Science Foundation (DR), and by the Swiss NationalCenter of Competence in Research "Materials with NovelElectronic Properties-MaNEP" (CH).

- <sup>1</sup> R.K leiner, F.Steinm eyer, G.K unkel, and P.M uller, Phys. Rev.Lett. 68, 2394 (1992)
- <sup>2</sup> R.K leiner and P.M uller, Phys. Rev. B 49, 1327 (1994); P.M uller in: Festkorperproblem e/Advances in Solid State Physics, Vol 34, ed. by Helbig R (Vieweg, Braunschweig), 1 (1994)
- <sup>3</sup> A. Yurgens, D. W inkler, N.V. Zavaritsky, T. Claeson, Phys.Rev.53, R8887 (1996);
- <sup>4</sup> T.Koyam a and M.Tachiki, Phys. Rev. B 54, 16183 (1996).
- <sup>5</sup> L N. Bulaevskii, D. D om inguez, M P. M aley, A R. Bishop, and B.I. Ivlev, Phys. Rev. B 53, 14601 (1996).
- <sup>6</sup> SN.Artem enko and A G.K obelkov, Phys.Rev.Lett.78, 3551 (1997).
- <sup>7</sup> D A.Ryndyk, Phys. Rev. Lett. 80, 3376 (1998).
- <sup>8</sup> C. Preis, C. Helm, J. Keller, A. Sergeev, and R. Kleiner, in Superconducting Superlattices II: Native and Articial, I. Bozovic and D. Pavona, editors, Proceedings of SPIE Volume 3480, 236 (1998).
- <sup>9</sup> S.E. Shafranjuk, M. Tachiki, Phys. Rev. B 59, 14087 (1999).
- <sup>10</sup> D A.Ryndyk, JETP 89, 975 (1999), Zh.Eksp.Teor.Fiz. 116, 1798 (1999)].
- <sup>11</sup> C.Helm, J.Keller, C.Preis, and A.Sergeev, Physica C 362 43 (2001).

- <sup>12</sup> D A.Ryndyk, J.K eller and C.Helm, J.Phys.: Condens. M atter 14, 815 (2002).
- <sup>13</sup> C.Helm, LN.Bulaevskii, EM. Chudnovsky, MP.Maley, Phys.Rev.Letters, 89, 057003 (2002).
- <sup>14</sup> L.N. Bulaevskii, C. Helm, A.R. Bishop, M.P. Maley, Europhys. Lett. 58 415 (2002; C. Helm, L.N. Bulevskii, condmath/0207491, submitted to Phys. Rev. B
- <sup>15</sup> J.C larke, Phys. Rev. Lett. 28, 1363 (1972); M.Tinkham, J.C larke, Phys. Rev. Lett. 28, 1366 (1972).
- <sup>16</sup> A.Schmid, G.Schon, J.Low Temp.Phys. 31, 1 (1975).
- <sup>17</sup> M. Tinkham, Introduction to Superconductivity, second edition, M oG raw -H ill (1996), Chapter 11.
- <sup>18</sup> S. Rother, R. Kleiner, P. Muller, Y. Kasai, K. Nakajima, Physica C 341-348 1565 (2000; S. Rother, Y. Koval, P. Muller, R. Kleiner, Y. Kasai, K. Nakajima, M. Darula, IEEE Trans. Appl. Superconductivity 11, 1191 (2001)
- <sup>19</sup> H B.W ang, P H.W u, T.Yam ashita, Phys. Rev. Lett. 87, 107002 (2001); H B.W ang, L X.You, J.Chen, P H.W u, T.Yam ashita, Supercond. Sci. Technol. 15 90 (2002)
- <sup>20</sup> Y J.Doh, J.K m, K.T.K m, and H J.Lee, Phys. Rev. B 61, R 3834 (2000).
- <sup>21</sup> W .N essler, S.O gawa, H.N agano, H.Petek, J.Shim oyama, Y.N akayama, K.K ishio, Phys. Rev. Lett. 81, 4480 (1998)